# International Rectifier

# IRF5305PbF

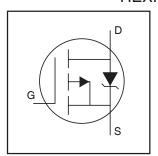
HEXFET® Power MOSFET

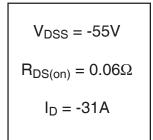
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Lead-Free

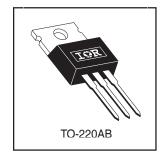
### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







### **Absolute Maximum Ratings**

	•			
	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-31		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-22	A	
I <sub>DM</sub>	Pulsed Drain Current ①	-110		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	110	W	
	Linear Derating Factor	0.71	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy®	280	mJ	
I <sub>AR</sub>	Avalanche Current①	-16	А	
E <sub>AR</sub>	Repetitive Avalanche Energy①	11	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )		
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)		

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.4	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

# IRF5305PbF

International
Rectifier

### Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-55			V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.034		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.06	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -16A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
9 <sub>fs</sub>	Forward Transconductance	8.0			S	$V_{DS} = -25V, I_{D} = -16A$
1	Drain-to-Source Leakage Current			-25		$V_{DS} = -55V, V_{GS} = 0V$
I <sub>DSS</sub>	Diam-to-Source Leakage Current			-250	μA	V <sub>DS</sub> = -44V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			63		I <sub>D</sub> = -16A
Q <sub>gs</sub>	Gate-to-Source Charge			13	nC	$V_{DS} = -44V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge			29		$V_{GS}$ = -10V, See Fig. 6 and 13 $\oplus$
t <sub>d(on)</sub>	Turn-On Delay Time		14			$V_{DD} = -28V$
t <sub>r</sub>	Rise Time		66		_	$I_D = -16A$
t <sub>d(off)</sub>	Turn-Off Delay Time		39		ns	$R_G = 6.8\Omega$
t <sub>f</sub>	Fall Time		63			$R_D = 1.6\Omega$ , See Fig. 10 ④
1-	Internal Drain Inductance		4.5			Between lead,
L <sub>D</sub>	Internal Dialit Inductance		4.5		nH	6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		11111	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		1200			$V_{GS} = 0V$
Coss	Output Capacitance		520		pF	$V_{DS} = -25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		250			f = 1.0MHz, See Fig. 5

### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			-31		MOSFET symbol
	(Body Diode)			-31	Α	showing the
I <sub>SM</sub>	Pulsed Source Current		110		integral reverse	
	(Body Diode) ①			-110	p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage			-1.3	V	$T_J = 25^{\circ}C$ , $I_S = -16A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		71	110	ns	$T_J = 25^{\circ}C, I_F = -16A$
Q <sub>rr</sub>	Reverse RecoveryCharge		170	250	nC	di/dt = -100A/µs ⊕

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\begin{tabular}{ll} $\mathbb{O}$ $V_{DD}=$-25V, starting $T_J=25^{\circ}C$, $L=2.1mH$ \\ $R_G=25\Omega$, $I_{AS}=$-16A. (See Figure 12) \\ \end{tabular}$
- $\label{eq:loss} \begin{array}{l} \text{ } 3 \text{ } I_{SD} \leq \text{-16A, di/dt} \leq \text{-280A/}\mu\text{s, } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}\text{C} \end{array}$
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .

# International TOR Rectifier

# IRF5305PbF

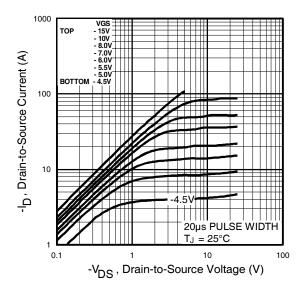


Fig 1. Typical Output Characteristics

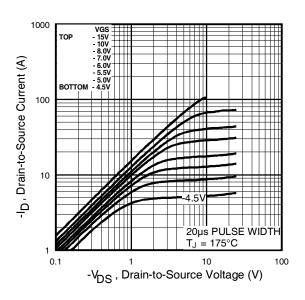


Fig 2. Typical Output Characteristics

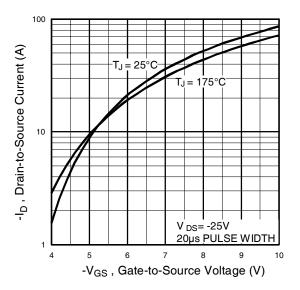
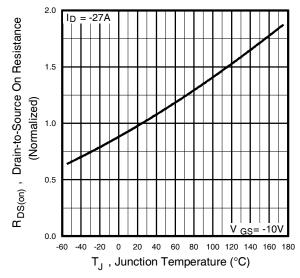
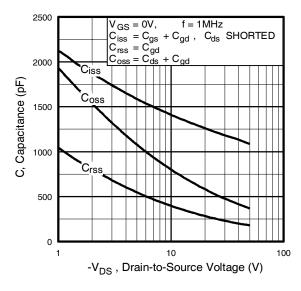


Fig 3. Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

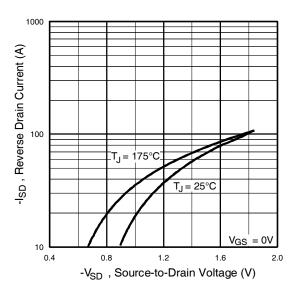
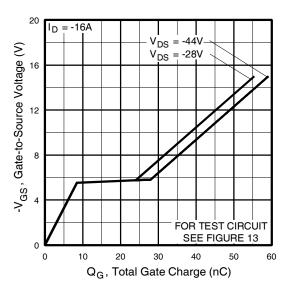


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

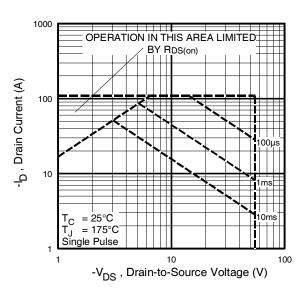
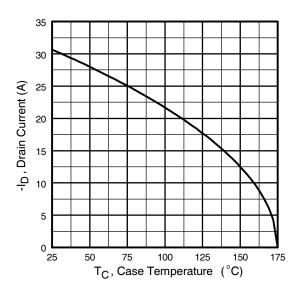


Fig 8. Maximum Safe Operating Area

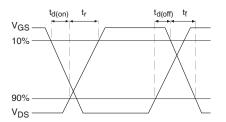
# International TOR Rectifier

# IRF5305PbF



 $V_{DS}$   $V_{GS}$   $P_{G}$   $P_{US}$   $V_{DS}$   $V_{DS}$   $V_{DS}$   $V_{DU}$   $V_$ 

Fig 10a. Switching Time Test Circuit



**Fig 9.** Maximum Drain Current Vs. Case Temperature

Fig 10b. Switching Time Waveforms

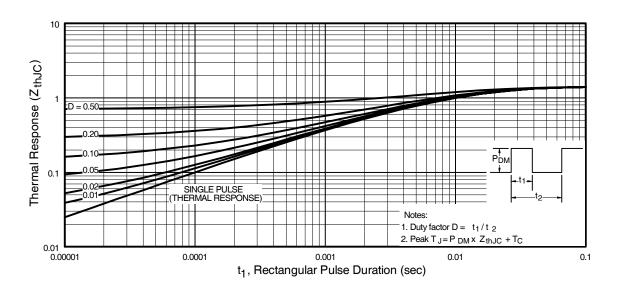


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

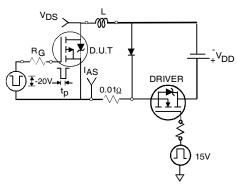


Fig 12a. Unclamped Inductive Test Circuit

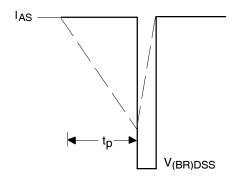


Fig 12b. Unclamped Inductive Waveforms

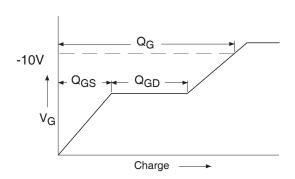
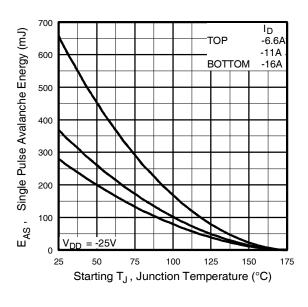


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

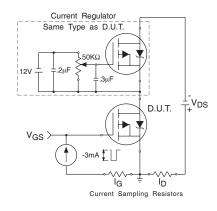
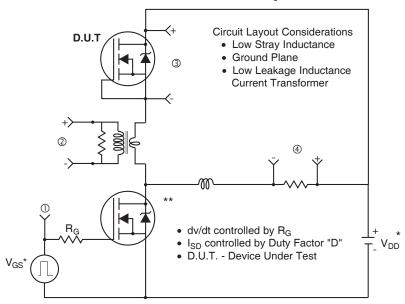


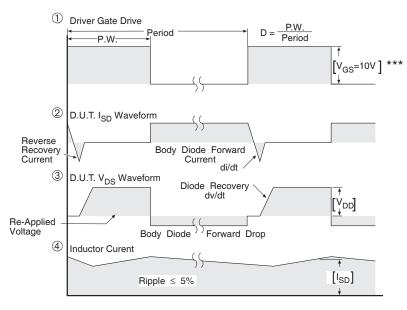
Fig 13b. Gate Charge Test Circuit

# IRF5305PbF

### Peak Diode Recovery dv/dt Test Circuit



- \* Reverse Polarity for P-Channel
- \*\* Use P-Channel Driver for P-Channel Measurements



\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

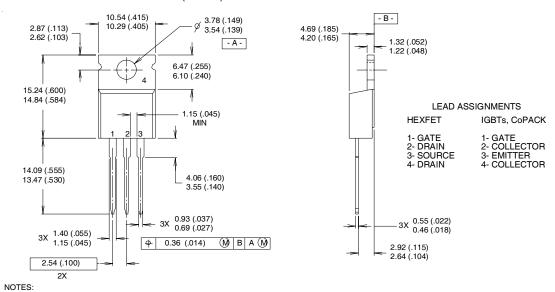
### IRF5305PbF

International

TOR Rectifier

### TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.

2 CONTROLLING DIMENSION: INCH

4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

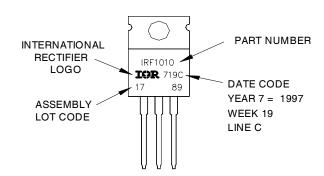
### TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information.10/03

Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>